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## **TEST REPORT**

**Product** : Head up display

Trade mark : IRIS

Model/Type reference : IRIS1

Serial Number : N/A

Report Number : EED32H000747-1

FCC ID : 2AHJD-IRIS1

**Date of Issue:** : Nov. 06, 2015

**Test Standards**: 47 CFR Part 15 Subpart C (2014)

Test result : PASS

Prepared for:

DD TECHNOLOGIES INC 1380-885 West Georgia Street, Vancouver, B.C., V6C 3E8

Prepared by:

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Report Seal

XM Reviewed by:

Nov. 06, 2015

Sheek Luo

Lab supervisor

Check No.: 1996294263









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### 2 Version

Version No.	Date	Description	
00	Nov. 06, 2015	Original	
			(6,1)











































































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## 3 Test Summary

Test Requirement	Test method	<b>Result</b> PASS	
47 CFR Part 15, Subpart C Section 15.203/15.247 (c)	ANSI C63.10-2013		
47 CFR Part 15, Subpart C Section 15.207	ANSI C63.10-2013	N/A	
47 CFR Part 15, Subpart C Section 15.247 (b)(3)	ANSI C63.10-2013	PASS	
47 CFR Part 15, Subpart C Section 15.247 (a)(2)	ANSI C63.10-2013	PASS	
47 CFR Part 15, Subpart C Section 15.247 (e)	ANSI C63.10-2013	PASS	
47 CFR Part 15, Subpart C Section 15.247(d)	ANSI C63.10-2013	PASS	
47 CFR Part 15, Subpart C Section 15.247(d)	ANSI C63.10-2013	PASS	
47 CFR Part 15, Subpart C Section 15.205/15.209	ANSI C63.10-2013	PASS	
47 CFR Part 15, Subpart C Section 15.205/15.209	ANSI C63.10-2013	PASS	
	47 CFR Part 15, Subpart C Section 15.203/15.247 (c)  47 CFR Part 15, Subpart C Section 15.207  47 CFR Part 15, Subpart C Section 15.247 (b)(3)  47 CFR Part 15, Subpart C Section 15.247 (a)(2)  47 CFR Part 15, Subpart C Section 15.247 (e)  47 CFR Part 15, Subpart C Section 15.247(d)  47 CFR Part 15, Subpart C Section 15.247(d)  47 CFR Part 15, Subpart C Section 15.247(d)  47 CFR Part 15, Subpart C Section 15.205/15.209  47 CFR Part 15, Subpart C Section	47 CFR Part 15, Subpart C Section 15.203/15.247 (c)       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.207       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.247 (b)(3)       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.247 (a)(2)       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.247 (e)       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.247(d)       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.247(d)       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.205/15.209       ANSI C63.10-2013         47 CFR Part 15, Subpart C Section 15.205/15.209       ANSI C63.10-2013	

Test according to ANSI C63.4-2014 & ANSI C63.10-2013.







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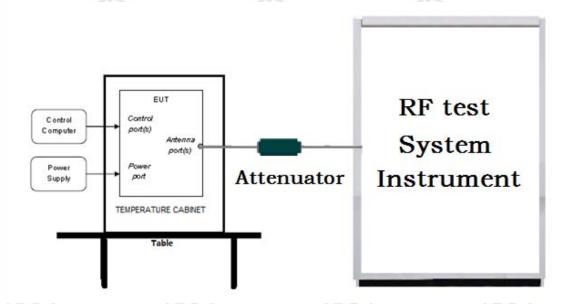


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## 5 Test Requirement

### 5.1 Test setup

## 5.1.1 For Conducted test setup



### 5.1.2 For Radiated Emissions test setup

Radiated Emissions setup:

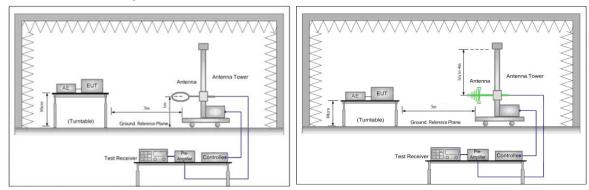


Figure 1. Below 30MHz

Figure 2. 30MHz to 1GHz

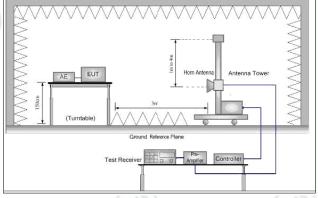


Figure 3. Above 1GHz





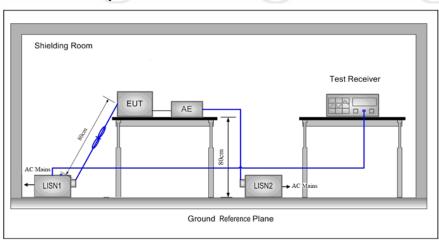




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# 5.1.3 For Conducted Emissions test setup Conducted Emissions setup



### **5.2 Test Environment**

Operating Environment:			
Temperature:	24 °C		
Humidity:	53 % RH		
Atmospheric Pressure:	1010mbar	(67)	(67)

### **5.3 Test Condition**

	Test Mode	Ty/Dy		RF Channel	100
6	rest Mode	Tx/Rx	Low(L)	Middle(M)	High(H)
1	CECK	2402MH= 2490 MH=	Channel 1	Channel 20	Channel 40
	GFSK	2402MHz ~2480 MHz	2402MHz	2440MHz	2480MHz





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### 6 General Information

### **6.1 Client Information**

Applicant:	DD TECHNOLOGIES INC
Address of Applicant:	1380-885 West Georgia Street, Vancouver, B.C., V6C 3E8
Manufacturer:	UMEC(SHENZHEN) COMPANY LTD
Address of Manufacturer:	No.18,Hao Ye Rd., Tong Fu Yu Industrial Park, Fu Yong Town, Baoan, Shenzhen, China

## 6.2 General Description of EUT

Product Name:	Head up display		
Model No.(EUT):	IRIS1		
Trade mark:	IRIS		
EUT Supports Radios application:	Bluetooth V4.0	(3)	Cis
Power Supply:	Input: 12V=== 650mA, Class III	(0,)	(C)
Sample Received Date:	Jul.16, 2015		
Sample tested Date:	Jul. 16, 2015 to Nov. 06, 2015		

## 6.3 Product Specification subjective to this standard

/ / / / -	/ / / / /		
Operation Frequency:	2402MHz~2480MHz		
Bluetooth Version:	4.0		
Modulation Type:	GFSK		
Number of Channel:	40	_°	(2)
Sample Type:	Fixed production	(27)	(27)
Antenna Type:	Integral		
Antenna Gain:	0dBi		
Test Voltage:	DC 12V		

#### Operation Frequency each of channel

Operation Frequency each of channel				10.7		16.7	
Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency
1	2402MHz	11	2422MHz	21	2442MHz	31	2462MHz
2	2404MHz	12	2424MHz	22	2444MHz	32	2464MHz
3	2406MHz	13	2426MHz	23	2446MHz	33	2466MHz
4	2408MHz	14	2428MHz	24	2448MHz	34	2468MHz
5	2410MHz	15	2430MHz	25	2450MHz	35	2470MHz
6	2412MHz	16	2432MHz	26	2452MHz	36	2472MHz
7	2414MHz	17	2434MHz	27	2454MHz	37	2474MHz
8	2416MHz	18	2436MHz	28	2456MHz	38	2476MHz
9	2418MHz	19	2438MHz	29	2458MHz	39	2478MHz
10	2420MHz	20	2440MHz	30	2460MHz	40	2480MHz



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### 6.4 Description of Support Units

The EUT has been tested with associated equipment below:

Device Type	Brand	Model	Data Cable	Remark
	(	<u>~</u>		(3
(0,	/	3		(6)

#### 6.5 Test Location

All tests were performed at:

Centre Testing International (Shenzhen) Corporation

Building C, Scientific Innovation Park, Tiegang Reservior, Xixiang, Baoan District, Shenzhen, China

Telephone: +86 (0) 755 3368 3668 Fax:+86 (0) 755 3368 3385

No tests were sub-contracted.

### 6.6 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

CNAS-Lab Code: L1910

Centre Testing International Group Co., Ltd. has been assessed and proved to be in compliance with CNAS-CL01 Accreditation Criteria for Testing and Calibration Laboratories (identical to ISO/IEC 17025: 2005 General Requirements) for the Competence of Testing and Calibration Laboratories..

#### A2LA-Lab Cert. No. 3061.01

Centre Testing International Group Co., Ltd. EMC Laboratory has been accredited by A2LA for technical competence in the field of electrical testing, and proved to be in compliance with ISO/IEC 17025: 2005 General Requirements for the Competence of Testing and Calibration Laboratories and any additional program requirements in the identified field of testing.

#### FCC-Registration No.: 565659

Centre Testing International Group Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the FCC (Federal Communications Commission). The acceptance letter from the FCC is maintained in our files. Registration 565659.

#### IC-Registration No.: 7408A

The 3m Alternate Test Site of Centre Testing International Group Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for the performance of radiated measurements with Registration No. 7408A.

#### IC-Registration No.: 7408B

The 10m Alternate Test Site of Centre Testing International Group Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for the performance of radiated measurements with Registration No. 7408B.



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#### NEMKO-Aut. No.: ELA503

Centre Testing International Group Co., Ltd. has been assessed the quality assurance system, the testing facilities, qualifications and testing practices of the relevant parts of the organization. The quality assurance system of the Laboratory has been validated against ISO/IEC 17025 or equivalent. The laboratory also fulfils the conditions described in Nemko Document NLA-10.

#### VCCI

The Radiation 3 &10 meters site of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-4096.

Main Ports Conducted Interference Measurement of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: C-4563.

Telecommunication Ports Conducted Disturbance Measurement of

Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: T-2146.

The Radiation 3 meters site of Centre Testing International Group Co., Ltd. has been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-758

#### 6.7 Deviation from Standards

None.

6.8 Abnormalities from Standard Conditions

None.

6.9 Other Information Requested by the Customer

None.











## 6.10 Measurement Uncertainty (95% confidence levels, k=2)

No.	Item	Measurement Uncertainty
1	Radio Frequency	7.9 x 10 <sup>-8</sup>
0	DE novembrated	0.31dB (30MHz-1GHz)
2	RF power, conducted	0.57dB (1GHz-18GHz)
3	Padiated Courieus emission test	4.5dB (30MHz-1GHz)
	Radiated Spurious emission test	4.8dB (1GHz-12.75GHz)
	Conduction emission	3.6dB (9kHz to 150kHz)
4	Conduction emission	3.2dB (150kHz to 30MHz)
5	Temperature test	0.64°C
6	Humidity test	2.8%
7	DC power voltages	0.025%



























































## 7 Equipment List

		RF test s	system		
Equipment	Manufacturer	Mode No.	Serial Number	Cal. Date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)
Signal Generator	Keysight	E8257D	MY53401106	04-14-2015	04-13-2016
Communication test set test set	Agilent	N4010A	MY47230124	04-02-2015	04-01-2016
Spectrum Analyzer	Keysight	N9010A	MY54510339	04-01-2015	03-31-2016
Attenuator	HuaXiang	SHX370	15040701	04-01-2015	03-31-2016
Signal Generator	Keysight	N5182B	MY53051549	03-31-2015	03-30-2016
High-pass filter(3- 18GHz)	Sinoscite	FL3CX03WG18 NM12-0398-002	(6)	01-13-2015	01-12-2016
High-pass filter(5- 18GHz)	MICRO- TRONICS	SPA-F-63029-4		01-13-2015	01-12-2016
band rejection filter (GSM900)	Sinoscite	FL5CX01CA09C L12-0395-001		01-13-2015	01-12-2016
band rejection filter (GSM850)	Sinoscite	FL5CX01CA08C L12-0393-001		01-13-2015	01-12-2016
band rejection filter (GSM1800)	Sinoscite	FL5CX02CA04C L12-0396-002	(2)	01-13-2015	01-12-2016
band rejection filter (GSM1900)	Sinoscite	FL5CX02CA03C L12-0394-001	(C)	01-13-2015	01-12-2016
DC Power	Keysight	E3642A	MY54436035	03-31-2015	03-30-2016
PC-1	Lenovo	R4960d		04-01-2015	03-31-2016
BT&WI-FI Automatic control	R&S	OSPB157	101374	04-01-2015	03-31-2016
RF control unit	JS Tonscend	JS0806-2	2015860006	04-01-2015	03-31-2016
BT&WI-FI Automatic test software	JS Tonscend	JSTS1120-2		04-01-2015	03-31-2016

	Shielding Room No. 1 – Conduction Emission Test								
	Equipment Manufacture		Mode No.	Mode No. Serial Number		Cal. Due date (mm-dd-yyyy)			
١	Receiver	R&S	ESCI	100009	07-09-2015	07-08-2016			
1	LISN	R&S	ENV216	100098	11-12-2014	11-13-2015			



 $Hot line: 400-6788-333 \\ www.cti-cert.com \\ E-mail: info@cti-cert.com \\ Complaint call: 0755-33681700 \\ Complaint E-mail: complaint@cti-cert.com \\ Complaint call: 0755-33681700 \\ Complaint E-mail: complaint Call: 0755-33681700 \\ Call: 0$ 



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		3M Semi/full-anech	noic Chamber	•		
Equipment	quipment Manufacturer		Serial Number	Cal. date (mm-dd-yyyy)	Cal. Due date (mm-dd-yyyy)	
3M Chamber	TDK	SAC-3		06-02-2013	06-01-2016	
TRILOG Broadband Antenna	schwarzbeck	VULB9163	9163-617	07-14-2015	07-13-2016	
Microwave Preamplifier	Agilent	8449B	3008A02425	02-05-2015	02-04-2016	
Horn Antenna	ETS-LINDGREN	3117	00057410	07-08-2015	07-07-2016	
Loop Antenna	ETS	6502	00071730	07-23-2014	07-22-2015	
Loop Antenna	ETS	6502	00071730	07-23-2015	07-22-2016	
Spectrum Analyzer	R&S	FSP40	100416	07-09-2015	07-08-2016	
Receiver	R&S	ESCI	100435	07-09-2015	07-08-2016	
Multi device Controller	maturo	NCD/070/10711112		01-13-2015	01-12-2016	
LISN	schwarzbeck	NNBM8125	81251547	07-09-2015	07-08-2016	
LISN	schwarzbeck	NNBM8125	81251546	07-09-2015	07-08-2016	
Signal Generator Agilent		E4438C	MY45095744	04-19-2015	04-18-2016	
Signal Generator	Keysight	E8257D	MY53401106	04-14-2015	04-13-2016	
Temperature/ Humidity Indicator	TAYLOR	1451	5190	07-10-2015	07-09-2016	
Communication test set	Agilent	E5515C	GB47050533	01-13-2015	01-12-2016	
Cable line	Fulai(7M)	SF106	5219/6A	01-13-2015	01-12-2016	
Cable line	Fulai(6M)	SF106	5220/6A	01-13-2015	01-12-2016	
Cable line	Fulai(3M)	SF106	5216/6A	01-13-2015	01-12-2016	
Cable line	Fulai(3M)	SF106	5217/6A	01-13-2015	01-12-2016	
Communication test set	R&S	CMW500	152394	04-19-2015	04-18-2016	
High-pass filter(3- 18GHz)	Sinoscite	FL3CX03WG18NM 12-0398-002		01-13-2015	01-12-2016	
High-pass filter(5- 18GHz)	MICRO- TRONICS	SPA-F-63029-4		01-13-2015	01-12-2016	
band rejection filter	Sinoscite	FL5CX01CA09CL1 2-0395-001		01-13-2015	01-12-2016	
band rejection filter	Sinoscite	FL5CX01CA08CL1 2-0393-001		01-13-2015	01-12-2016	
band rejection filter	Sinoscite	FL5CX02CA04CL1 2-0396-002	(4)	01-13-2015	01-12-2016	
band rejection filter	Sinoscite	FL5CX02CA03CL1 2-0394-001	(C)	01-13-2015	01-12-2016	















## 8 Radio Technical Requirements Specification

Reference documents for testing:

N	lo.	Identity	Document Title
1		FCC Part15C (2014)	Subpart C-Intentional Radiators
2		ANSI C63.10-2013	American National Standard for Testing Unlicesed Wireless Devices

#### Test Results List:

est Nesults List.	( 4 )	( 4 3)		9.7
Test Requirement	Test method	Test item	Verdict	Note
Part15C Section 15.247 (a)(2)	ANSI C63.10	6dB Occupied Bandwidth	PASS	Appendix A)
Part15C Section 15.247 (b)(3)	ANSI C63.10	Conducted Peak Output Power	PASS	Appendix B)
Part15C Section 15.247(d)	ANSI C63.10	Band-edge for RF Conducted Emissions	PASS	Appendix C)
Part15C Section 15.247(d)	ANSI C63.10	RF Conducted Spurious Emissions	PASS	Appendix D)
Part15C Section 15.247 (e)	ANSI C63.10	Power Spectral Density	PASS	Appendix E)
Part15C Section 15.203/15.247 (c)	ANSI C63.10	Antenna Requirement	PASS	Appendix F)
Part15C Section 15.207	ANSI C63.10	AC Power Line Conducted Emission	N/A	N/A
Part15C Section 15.205/15.209 ANSI C63.10		Restricted bands around fundamental frequency (Radiated Emission)	PASS	Appendix G)
Part15C Section 15.205/15.209 K ANSI C63.10		Radiated Spurious Emissions	PASS	Appendix G)







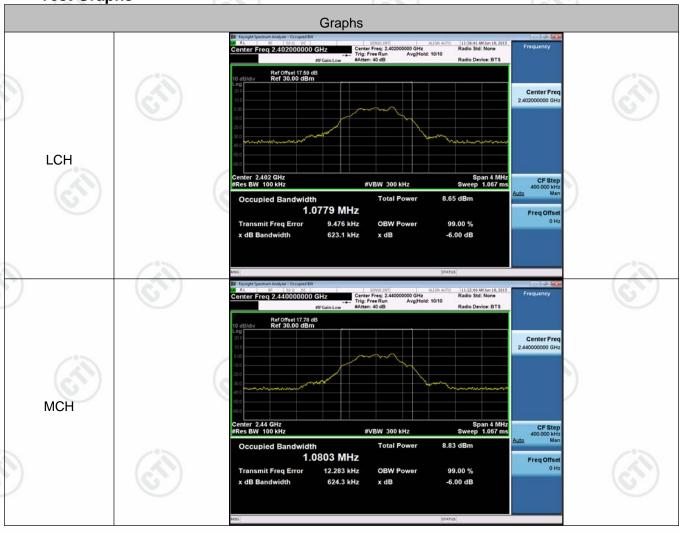
## Appendix A): 6dB Occupied Bandwidth

### **Test Result**

Mode	Channel	6dB Bandwidth [MHz]	99% OBW[MHz]	Verdict
BLE	LCH	0.623	1.0779	PASS
BLE	MCH	0.624	1.0803	PASS
BLE	НСН	0.624	1.0767	PASS

Remark: Peak detector is used.

**Test Graphs** 





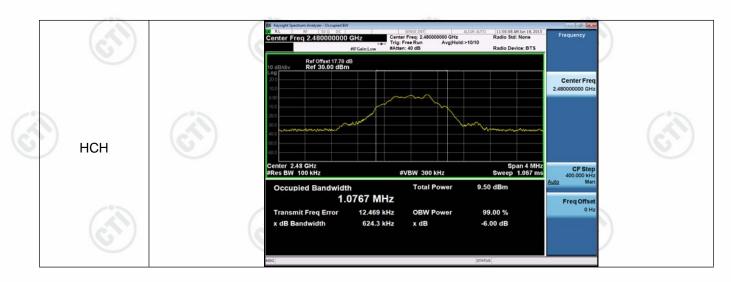








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## Appendix B): Conducted Peak Output Power

#### **Test Result**

Mode	Channel	Conduct Peak Power[dBm]	Verdict	
BLE	LCH	3.362	PASS	
BLE	MCH	3.370	PASS	
BLE	НСН	4.301	PASS	

**Test Graphs** 





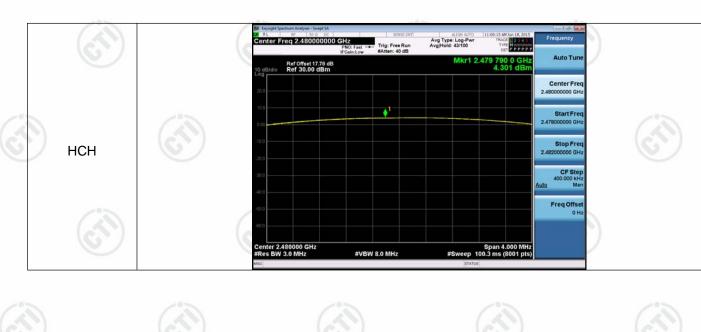








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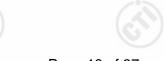








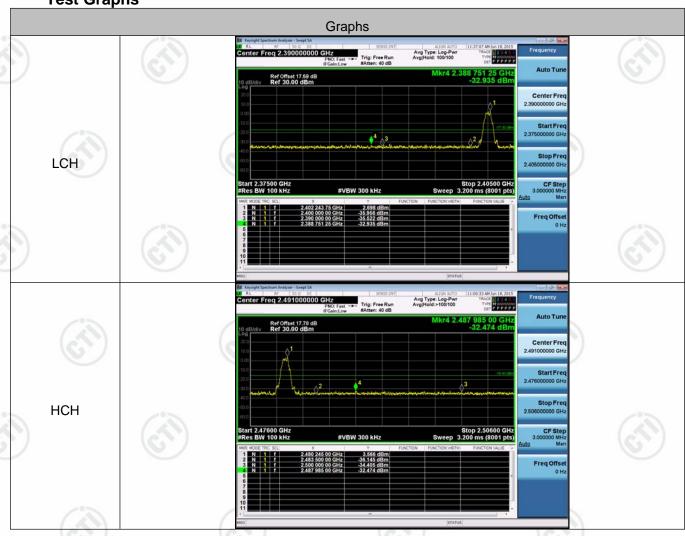




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## Appendix C): Band-edge for RF Conducted Emissions

**Test Graphs** 



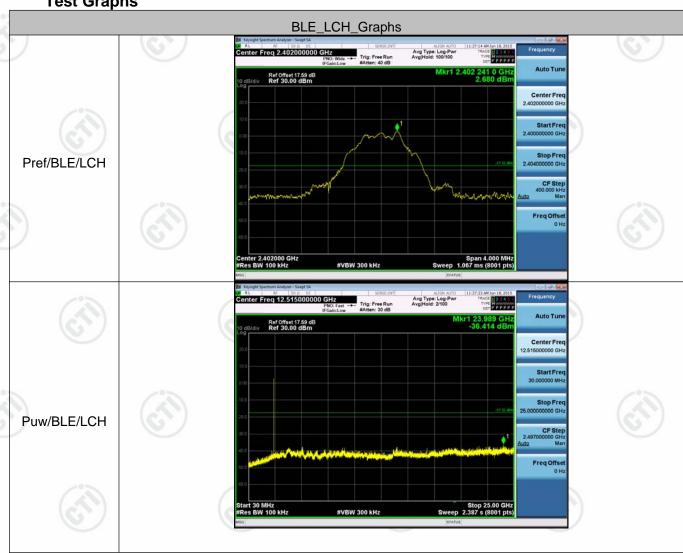


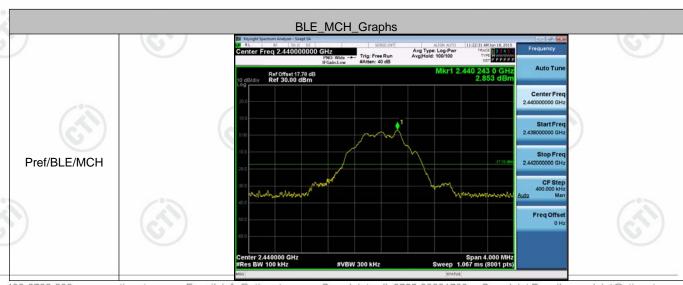


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## **Appendix D): RF Conducted Spurious Emissions**

**Test Graphs** 





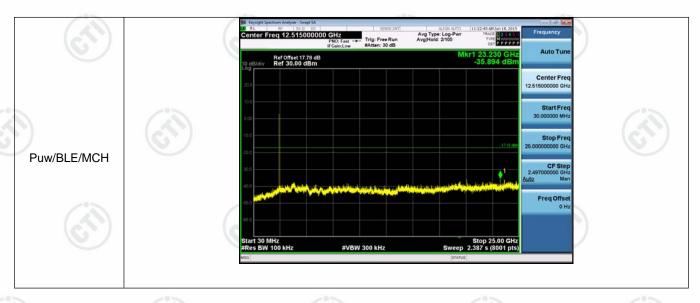
Hotline: 400-6788-333 www.cti-cert.com E-mail: info@cti-cert.com 

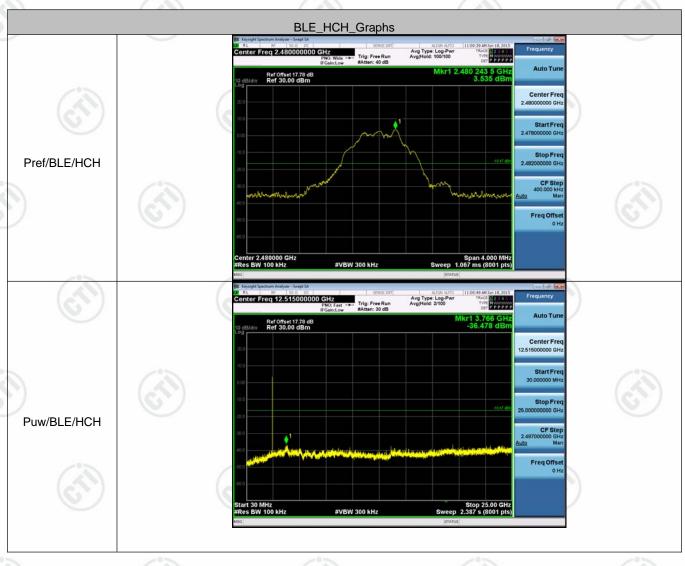














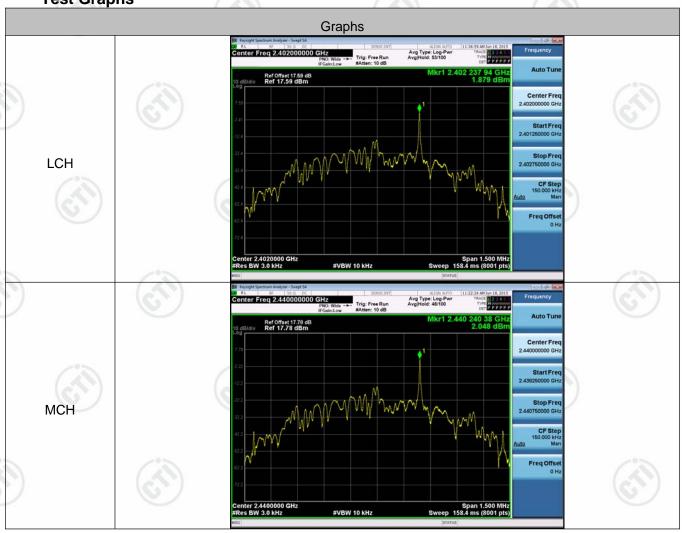


## **Appendix E): Power Spectral Density**

### **Result Table**

Mode	Channel	PSD [dBm]	Verdict
BLE	LCH	1.879	PASS
BLE	MCH	2.048	PASS
BLE	НСН	2.696	PASS

**Test Graphs** 





























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## Appendix F) Antenna Requirement

#### 15.203 requirement:

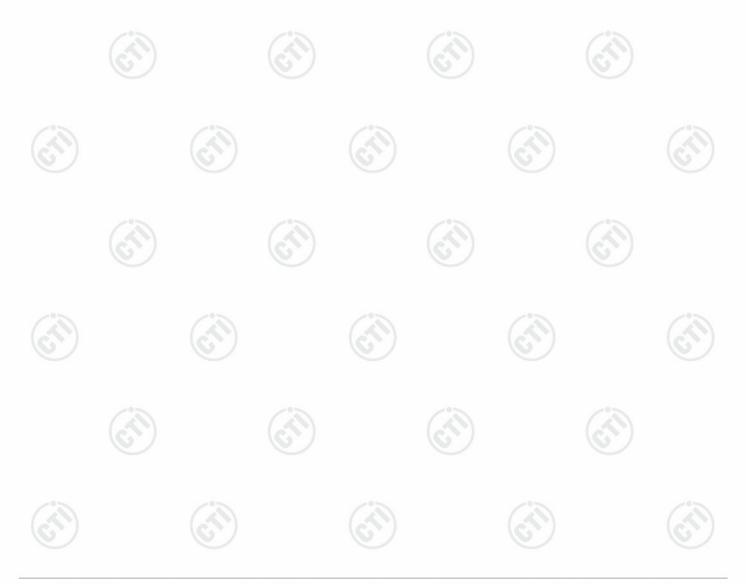
An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator, the manufacturer may design the unit so that a broken antenna car be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited.

#### 15.247(b) (4) requirement:

The conducted output power limit specified in paragraph (b) of this section is based on the use of antennas with directional gains that do not exceed 6 dBi. Except as shown in paragraph (c) of this section, if transmitting antennas of directional gain greater than 6 dBi are used, the conducted output power from the intentional radiator shall be reduced below the stated values in paragraphs (b)(1), (b)(2), and (b)(3) of this section, as appropriate, by the amount in dB that the directional gain of the antenna exceeds 6 dBi.

#### **EUT Antenna:**

The antenna is integrated on the main PCB and no consideration of replacement. The best case gain of the antenna is 0 dBi.









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# Appendix G) Restricted bands around fundamental frequency (Radiated)/Radiated Spurious Emissions

#### **Receiver Setup:**

Frequency	Detector	RBW	VBW	Remark
0.009MHz-0.090MHz	Peak	10kHz	30kHz	Peak
0.009MHz-0.090MHz	Average	10kHz	30kHz	Average
0.090MHz-0.110MHz	Quasi-peak	10kHz	30kHz	Quasi-peak
0.110MHz-0.490MHz	Peak	10kHz	30kHz	Peak
0.110MHz-0.490MHz	Average	10kHz	30kHz	Average
0.490MHz -30MHz	Quasi-peak	10kHz	30kHz	Quasi-peak
30MHz-1GHz	Quasi-peak	120 kHz	300kHz	Quasi-peak
Above 1GHz	Peak	1MHz	3MHz	Peak
Above 1GHz	Peak	1MHz	10Hz	Average

#### **Test Procedure:**

#### Below 1GHz test procedure as below:

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 meter semi-anechoic camber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The antenna height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters (for the test frequency of below 30MHz, the antenna was tuned to heights 1 meter) and the rotatable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e. The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- f. If the emission level of the EUT in peak mode was 10dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10dB margin would be re-tested one by one using peak, quasi-peak or average method as specified and then reported in a data sheet.

#### Above 1GHz test procedure as below:

- g. Test the EUT in the lowest channel ,the middle channel ,the Highest channel
- h. The radiation measurements are performed in X, Y, Z axis positioning for Transmitting mode, and found the X axis positioning which it is worse case.
- i. Repeat above procedures until all frequencies measured was complete.

m	

Frequency	Field strength (microvolt/meter)	Limit (dBµV/m)	Remark	Measurement distance (m)
0.009MHz-0.490MHz	2400/F(kHz)	- (abp (/////)	-(6)	300
0.490MHz-1.705MHz	24000/F(kHz)	-	-	30
1.705MHz-30MHz	30	-	-	30
30MHz-88MHz	100	40.0	Quasi-peak	3
88MHz-216MHz	150	43.5	Quasi-peak	3
216MHz-960MHz	200	46.0	Quasi-peak	3
960MHz-1GHz	500	54.0	Quasi-peak	3
Above 1GHz	500	54.0	Average	3

Note: 15.35(b), Unless otherwise specified, the limit on peak radio frequency emissions is 20dB above the maximum permitted average emission limit applicable to the equipment under test. This peak limit applies to the total peak emission level radiated by the device.













CII





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**Radiated Spurious Emissions test Data:** 

All the modes of operation (X, Y, Z) were investigated and the worst-case emissions are reported.

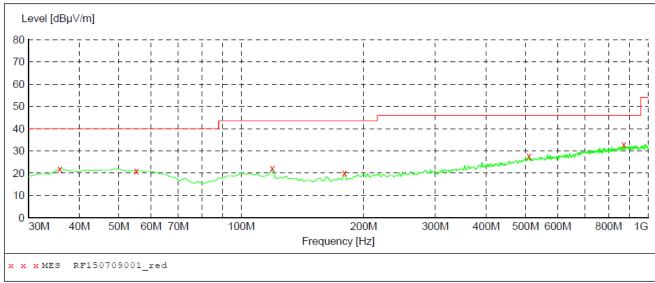
#### A. Below 30MHz:

No emissions were found higher than the background below 30MHz and background is lower than the limit, so it deems to compliance with the limit without recorded.

#### B. $30MHz \sim 1GHz$ :

The test data of low channel, middle channel and high channel are almost same in frequency bands 30MHz to 1GHz, and the data of middle channel (GFSK mode) are chosen as representative in below:

#### H:



Frequency MHz	Level dBµV/m			Margin dB	Height cm	Azimuth deg	Polarization
35.820000	22.00	14.9	40.0	18.0	 200.0	39.00	HORIZONTAL
55.220000	21.10	15.8	40.0	18.9	 100.0	370.00	HORIZONTAL
119.240000	22.10	13.3	43.5	21.4	 100.0	180.00	HORIZONTAL
179.380000	20.20	12.9	43.5	23.3	 200.0	12.00	HORIZONTAL
509.180000	27.70	21.6	46.0	18.3	 100.0	260.00	HORIZONTAL
871.960000	32.90	26.4	46.0	13.1	 100.0	340.00	HORIZONTAL



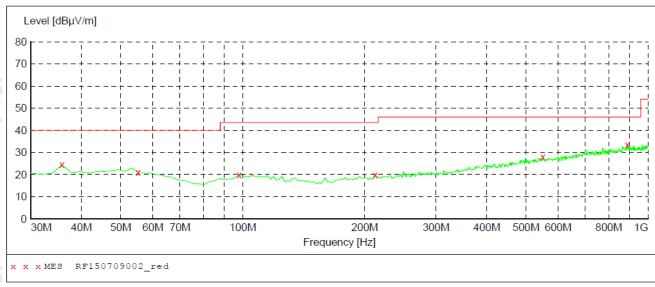






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#### ۷:



Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
35.820000 55.220000	24.40	14.9 15.8	40.0	15.6 19.0		100.0	318.00 48.00	VERTICAL VERTICAL
97.900000	19.90	14.4	43.5	23.6		100.0	277.00	VERTICAL
212.360000	20.00	14.1	43.5	23.5		100.0	367.00	VERTICAL
549.920000	27.90	21.8	46.0	18.1		100.0	370.00	VERTICAL
889.420000	33.40	26.6	46.0	12.6		200.0	238.00	VERTICAL

















































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#### C. Above 1GHz:

Test Results-(Measurement Distance: 3m)\_Channel low\_2402MHz\_GFSK mode:

Frequency (MHz)	Measurement (dBuV/m)	Limit (dBuV/m)	Detector Type	Antenna (H/V)	Result (P/F)
2390.0	36.49	74	PK	Н	Р
2400.0	45.39	74	PK	H	P W
2402.0*	84.49		PK	Н	Р
4804.0	41.65	74	PK	Н	Р
2390.0	36.42	74	PK	V	P
2400.0	43.63	74	PK	V	Р
2402.0*	85.89		PK	V	Р
4804.0	43.21	74	PK	V	Р

<sup>\*:</sup> fundamental frequency

Test Results-(Measurement Distance: 3m)\_Channel middle\_2440MHz\_GFSK mode:

Frequency (MHz)	Measurement (dBuV/m)	Limit (dBuV/m)	Detector Type	Antenna (H/V)	Result (P/F)
2440.0*	86.95	(a)	PK	н (д	Р
4880.0	44.29	74	PK	н	Р
2440.0*	87.51		PK	V	Р
4880.0	44.62	74	PK	V	Р

<sup>\*:</sup> fundamental frequency

Test Results-(Measurement Distance: 3m)\_Channel high\_2480MHz\_GFSK mode:

Frequency (MHz)	Measurement (dBuV/m)	Limit (dBuV/m)	Detector Type	Antenna (H/V)	Result (P/F)
2480.0*	86.41	ン <del></del>	PK	н 🤘	Р
2483.5	42.64	74	PK	Н	Р
4960.0	41.49	74	PK	Н	Р
2480.0*	87.63		PK	V	Р
2483.5	42.52	74	PK	V	P
4960.0	43.51	74	PK	V	Р

<sup>\*:</sup> fundamental frequency

#### Remark:

- 1. The above tables show that the frequencies peak data are all below the average limit, so the average data of these frequencies are deems to fulfill the average limits and not reported.
- 2. No emission found from 18GHz to 25GHz.
- 3. All outside of operating frequency band and restricted band specified are below 15.209.





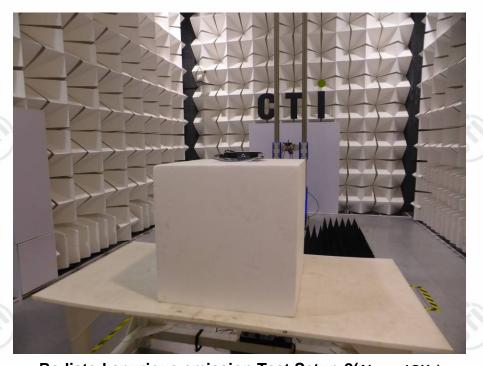
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## PHOTOGRAPHS OF TEST SETUP

Test mode No.: IRIS1



Radiated spurious emission Test Setup-1 (Below 1GHz)



Radiated spurious emission Test Setup-2(Above 1GHz)



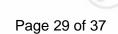
















View of external EUT-1













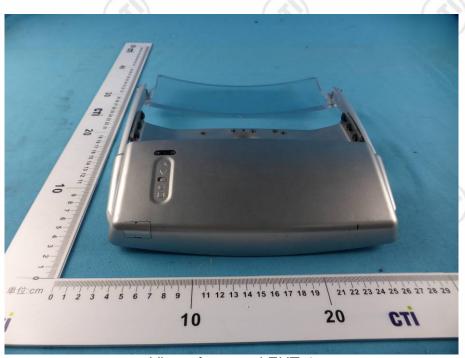








View of external EUT-3



View of external EUT-4





















View of external EUT-5



View of external EUT-6























View of internal EUT-1





View of internal EUT-2

















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View of internal EUT3



View of internal EUT-4









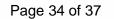


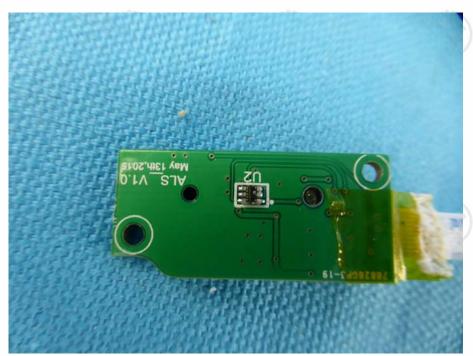












View of internal EUT-5



View of internal EUT-6











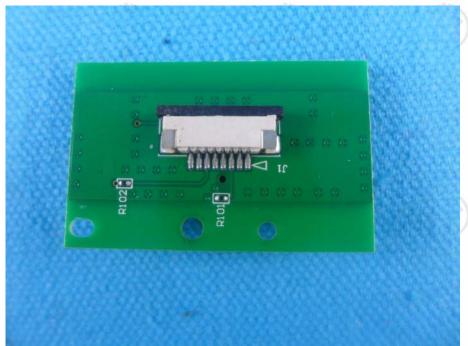












View of internal EUT-7





View of internal EUT-8





















View of internal EUT-9



View of internal EUT-10





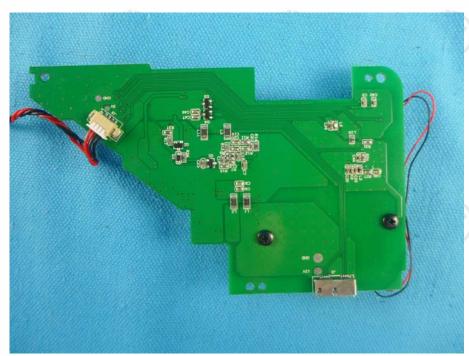




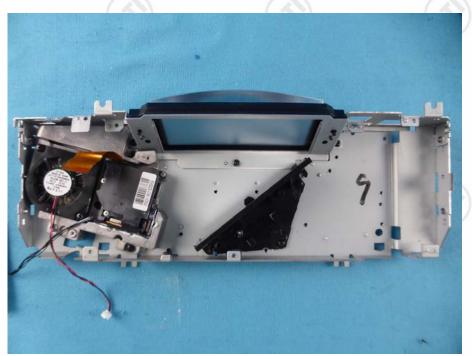




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View of internal EUT-11



View of internal EUT-12

\*\*\* End of Report \*\*\*

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